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TABLE OF CONTENTS

ADF-STEM Imaging of Strained GaN_{0.045}As_{0.955} Epitaxial Layers on (100) GaAs Substrates	1
<i>X. Wu, M. D. Robertson, J. A. Gupta, J. M. Baribeau, J. C. Bennet, M. Kawasaki, T. Aoki</i>	
Measurement of Moisture Migration Kinetics in Environmental Scanning Electron Microscopy	7
<i>X. Tang, M. De Rooij</i>	
Electron Tomography of SPM Probes, Nanoparticles and Precipitates	13
<i>X. Xu, Z. Saghi, G. Yang, Y. Peng, B. Inkson, R. Gay, G. Mobus</i>	
The Effect of Excess Carbon on the Crystallographic, Microstructural, and Mechanical Properties of CVD Silicon Carbide Fibers	19
<i>J. V. Marzik, W. J. Croft, R. J. Staples, W. J. Moberlychan</i>	
Comparison of Common Segmentation Techniques Applied to Transmission Electron Microscopy Images	25
<i>T. E. Sadowski, C. C. Broadbridge, J. Daponte</i>	
Microstructure Evolution in Deformed Copper and Nickel	31
<i>P. Landau, R. Z. Shneck, G. Makov, A. Venkert</i>	
Determination of Inelastic Mean Free Path by Electron Energy-Loss Spectroscopy in TEM: A Model Study using Si and Ge	37
<i>C. Wang, B. D. Cannon</i>	
Analytical TEM Observations of Au-Pd Nano-Particles Prepared by Sonochemical Techniques	42
<i>T. Akita, T. Hiroki, S. Tanaka, T. Kojima, M. Kohyama, A. Iwase, F. Hori</i>	
Author Index	